

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/591,458	MORIGUCHI ET AL.	
Examiner		Ronald A. Quinlan	Art Unit	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,066,399	05-2000	Hirano et al.	428/408
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Milton Ohring, Materials Science of Thin Films, Deposition and Structure, 2nd Ed., No month 2004, pg. 184, 748 and 749.
	V	D. Sheeja, et al., Tribological properties and adhesive strength of DLC coatings prepared under different substrate bias voltages, No month 2001, Wear 249, pg. 433-439.
	W	Fukaya et al., Machine translation of JP 2001-353603, 25 December 2001.
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.